

# **STL8N65M5**

# N-channel 650 V, 0.56 Ω, 7 A MDmesh<sup>™</sup> V Power MOSFET in PowerFLAT<sup>™</sup> 5x5

## Features

Order code	V <sub>DSS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STL8N65M5	710 V	< 0.6 Ω	7 A <sup>(1)</sup>

- 1. The value is rated according to  $R_{thj-case}$
- Worldwide best R<sub>DS(on)</sub> \* area
- Higher V<sub>DSS</sub> rating
- High dv/dt capability
- Excellent switching performance
- Easy to drive
- 100% avalanche tested

## **Applications**

Switching applications

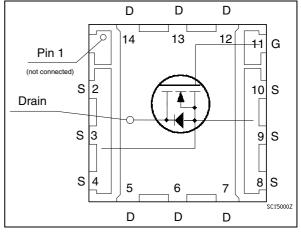
## Description

This device is an N-channel MDmesh<sup>™</sup> V Power MOSFET based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH<sup>™</sup> horizontal layout structure. The resulting product has extremely low onresistance, which is unmatched among siliconbased Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

Table 1.	Device	summary
----------	--------	---------

PowerFLAT™ 5x5
----------------

Figure 1. Internal schematic diagram



Order code	Marking	Package	Packaging	
STL8N65M5	8N65M5	PowerFLAT™ 5x5	Tape and reel	

# Contents

1	Electrical ratings	3
2	Electrical characteristics	4
	2.1 Electrical characteristics (curves)	6
3	Test circuits	8
4	Package mechanical data	9
5	Revision history1	2



## 1

# Electrical ratings

Symbol	Parameter	Value	Unit	
$V_{DS}$	Drain-source voltage ( $V_{GS} = 0$ )	650	V	
V <sub>GS</sub>	Gate-source voltage	± 25	V	
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at $T_C = 25 \ ^{\circ}C$	7	Α	
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at $T_C = 100 \ ^{\circ}C$	4.4	Α	
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at $T_{amb} = 25 \ ^{\circ}C$	1.4	Α	
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at $T_{amb} = 100 \ ^{\circ}C$	0.6	Α	
I <sub>DM</sub> <sup>(2),(3)</sup>	Drain current (pulsed)	5.6	Α	
P <sub>TOT</sub> <sup>(2)</sup>	Total dissipation at T <sub>amb</sub> = 25 °C	2.5	W	
P <sub>TOT</sub> <sup>(1)</sup>	Total dissipation at $T_C = 25 \ ^{\circ}C$	70	W	
I <sub>AR</sub> Avalanche current, repetitive or not- repetitive (pulse width limited by T <sub>i</sub> max)		2	A	
$E_{AS}$ Single pulse avalanche energy (starting T <sub>i</sub> = 25 °C, I <sub>D</sub> = I <sub>AR</sub> , V <sub>DD</sub> = 50 V)		120	mJ	
dv/dt (4)	Peak diode recovery voltage slope	15	V/ns	
T <sub>stg</sub>	Storage temperature	- 55 to 150	°C	
Тj	Max. operating junction temperature	150	°C	

#### Table 2. Absolute maximum ratings

1. The value is rated according to R<sub>thj-case</sub>

2. When mounted on FR-4 board of inch<sup>2</sup>, 2oz Cu

3. Pulse with limited by safe operating area.

4.  $I_{SD} \leq 7 \text{ A}, \text{ di/dt} \leq 400 \text{ A/}\mu\text{s}, \text{ V}_{\text{Peak}} < \text{ V}_{(BR)DSS}, \text{ V}_{DD} = 400 \text{ V}.$ 

#### Table 3.Thermal data

Symbol Parameter		Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max	1.78	°C/W
R <sub>thj-pcb</sub> <sup>(1)</sup> Thermal resistance junction-pcb max		60	°C/W

1. When mounted on 1inch<sup>2</sup> FR-4 board, 2 oz Cu



#### **Electrical characteristics** 2

(T<sub>C</sub> = 25 °C unless otherwise specified)

Symbol Parameter		Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage (V <sub>GS</sub> = 0)	I <sub>D</sub> = 1 mA	650			V
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = 650 V V <sub>DS</sub> = 650 V, T <sub>C</sub> =125 °C			1 100	μΑ μΑ
$I_{GSS}$ Gate-body leakage current (V <sub>DS</sub> = 0) $V_{GS} = \pm 25 V$				100	nA	
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	3	4	5	V
R <sub>DS(on)</sub>	Static drain-source on resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 3.5 A		0.56	0.6	Ω

#### Table 4. On /off states

Table 5. Dynamic

	Dynamo					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	V <sub>DS</sub> = 100 V, f = 1 MHz, V <sub>GS</sub> = 0	-	690 18 2	-	pF pF pF
C <sub>o(tr)</sub> <sup>(1)</sup>	Equivalent capacitance time related	V <sub>DS</sub> = 0 to 520 V, V <sub>GS</sub> = 0	-	17	-	pF
C <sub>o(er)</sub> <sup>(2)</sup>	Equivalent capacitance energy related	$v_{\rm DS} = 0.00320$ v, $v_{\rm GS} = 0.00320$	-	52	-	pF
R <sub>G</sub>	Intrinsic gate resistance	f = 1 MHz open drain	-	2.4	-	Ω
Qg	Total gate charge	V <sub>DD</sub> = 520 V, I <sub>D</sub> = 3.5 A,		15		nC
Q <sub>gs</sub>	Gate-source charge	V <sub>GS</sub> = 10 V	-	3.6	-	nC
Q <sub>gd</sub>	Gate-drain charge	(see Figure 15)		6		nC

C<sub>oss eq</sub> time related is defined as a constant equivalent capacitance giving the same charging time as C<sub>oss</sub> when V<sub>DS</sub> increases from 0 to 80% V<sub>DSS</sub>
 C<sub>oss eq</sub> energy related is defined as a constant equivalent capacitance giving the same stored energy as C<sub>oss</sub> when V<sub>DS</sub> increases from 0 to 80% V<sub>DSS</sub>



	e mitering timee					
Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t <sub>d(off)</sub>	Turn-off delay time	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 4 \text{ A},$		50		ns
t <sub>r (V)</sub>	Rise time	$R_{G} = 4.7 \Omega$ , $V_{GS} = 10 V$	_	14	_	ns
t <sub>c(off)</sub>	Cross time	(see Figure 16),	_	20	_	ns
t <sub>f (i)</sub>	Fall time	(see Figure 19)		11		ns

Table 6.Switching times

### Table 7.Source drain diode

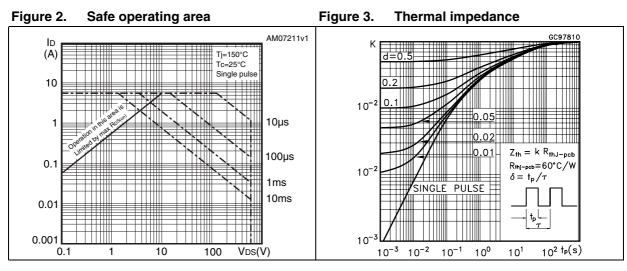
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current Source-drain current (pulsed)		-		7 28	A A
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 7 A, V <sub>GS</sub> = 0	-		1.5	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	I <sub>SD</sub> = 7A, di/dt = 100 A/μs V <sub>DD</sub> = 100 V (see <i>Figure 16</i> )	-	200 1.6 16		ns μC Α
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	I <sub>SD</sub> = 7 A, di/dt = 100 A/μs V <sub>DD</sub> = 100 V, T <sub>j</sub> = 150 °C (see <i>Figure 16</i> )	-	263 1.9 15		ns μC Α

1. Pulse width limited by safe operating area

2. Pulsed: pulse duration = 300  $\mu$ s, duty cycle 1.5%

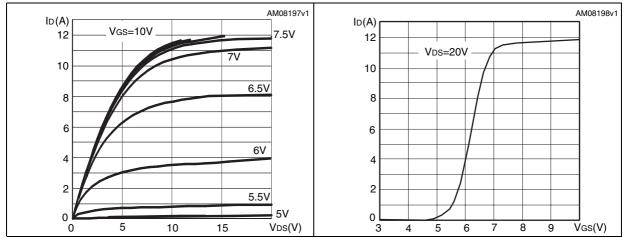


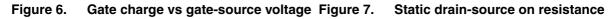
## 2.1 Electrical characteristics (curves)

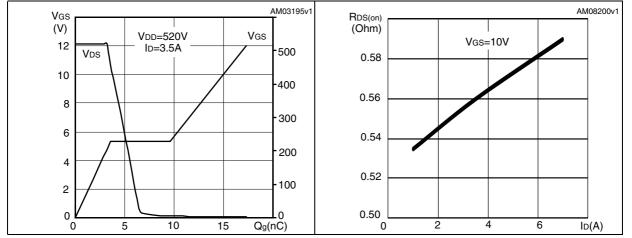












Doc ID 019013 Rev 3



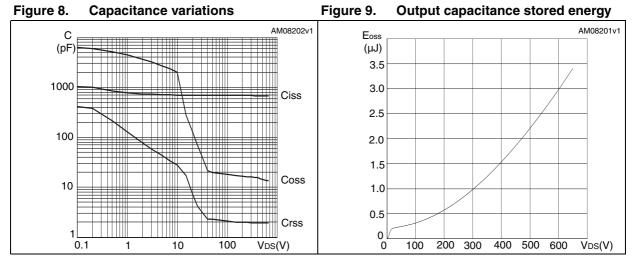


Figure 10. Normalized gate threshold voltage Figure 11. Normalized on resistance vs vs temperature temperature

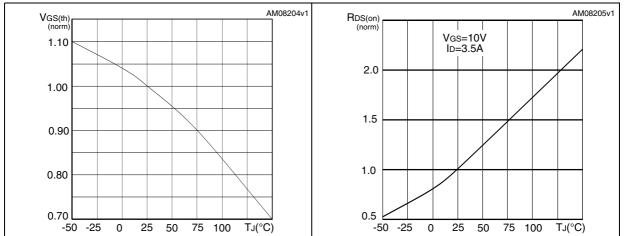
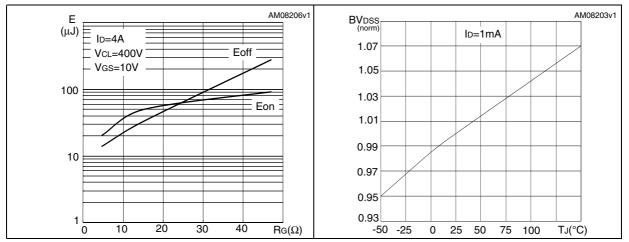


Figure 12. Switching losses vs gate resistance Figure 13. Normalized  $B_{VDSS}$  vs temperature (1)

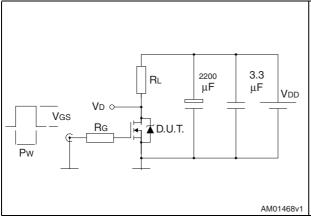


1. Eon including reverse recovery of a SiC diode



## 3 Test circuits

Figure 14. Switching times test circuit for resistive load



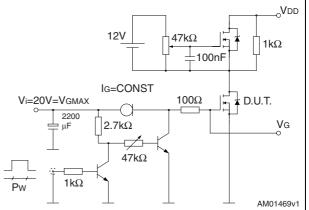
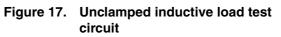


Figure 16. Test circuit for inductive load switching and diode recovery times



I

JJJJ

D.U.T.

2200

μF

3.3

μF

Vdd

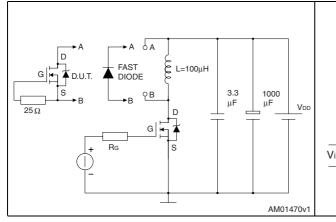
AM01471v1

VD O

lр

Pw

0



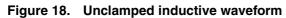


Figure 19. Switching time waveform

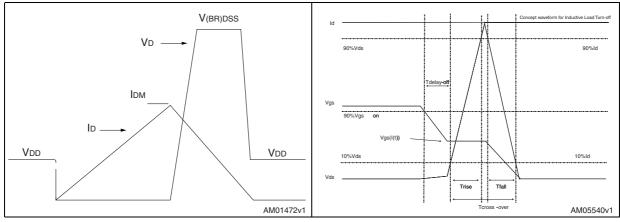


Figure 15. Gate charge test circuit



## 4 Package mechanical data

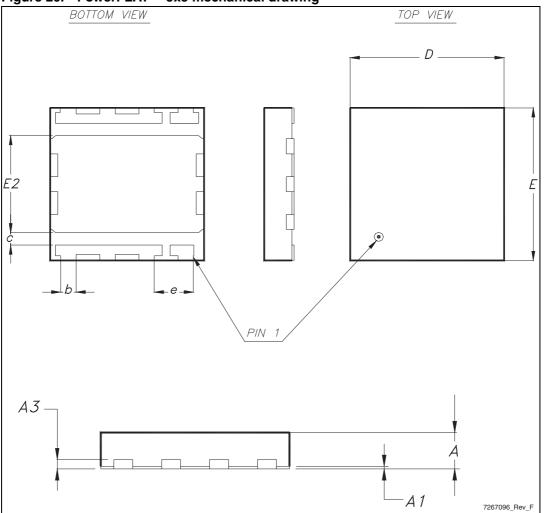
In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.



Dim.		mm			
Dim.	Min.	Тур.	Max.		
А	0.80	0.90	1.0		
A1	0	0.02	0.05		
A3		0.24			
D	4.90	5.0	5.10		
E	4.90	5.0	5.10		
E2	2.49	2.57	2.64		
е	1.22	1.27	1.32		
b	0.43	0.51	0.58		
С	0.64	0.71	0.79		

 Table 8.
 PowerFLAT™ 5x5 mechanical dimensions





Doc ID 019013 Rev 3



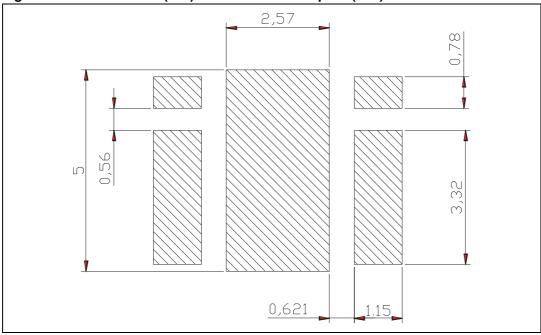


Figure 21. PowerFLAT™(5x5) recommended footprint (mm)



# 5 Revision history

Table 9.	<b>Document revision</b>	n history
	Document revision	I IIISLUI Y

Date	Revision	Changes	
05-Jul-2011	1	First release	
07-Jul-2011	2	Updated Figure 1.	
08-Aug-2011	3	Updated <i>Figure 3: Thermal impedance</i> . and R <sub>thj-pcb</sub> value in <i>Table 3: Thermal data</i> . Minor text changes.	



#### Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY TWO AUTHORIZED ST REPRESENTATIVES, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2011 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan -Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com



Doc ID 019013 Rev 3